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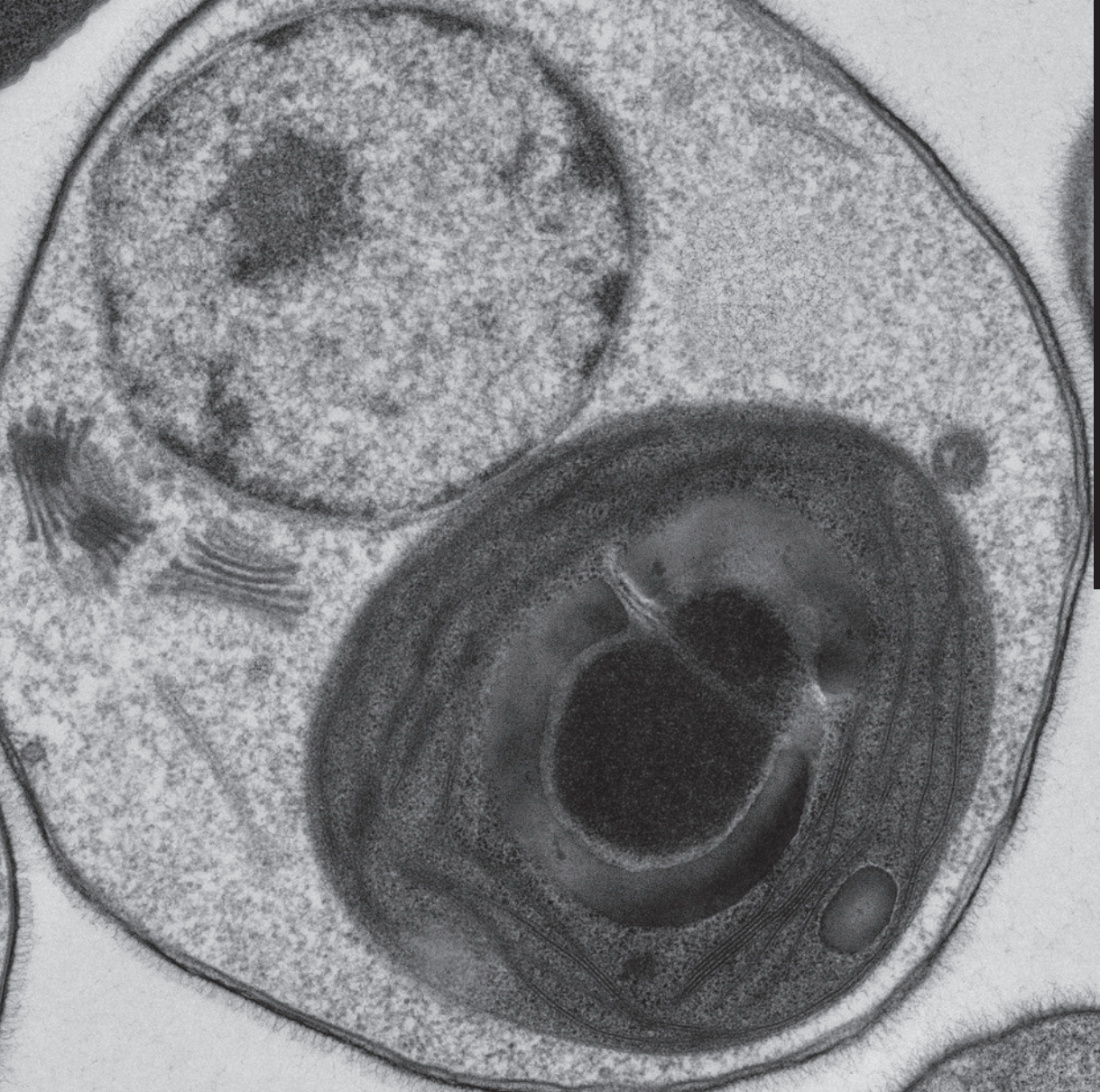
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Microscopy AND Microanalysis



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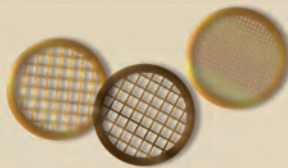


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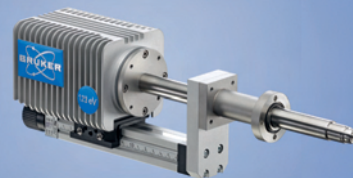
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Volume 16, Number 3

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INSTRUMENTATION AND SOFTWARE: DEVELOPMENT AND APPLICATIONS

Three-Dimensional Optical Sectioning by Scanning Confocal Electron Microscopy with a Stage-Scanning System 233

Ayako Hashimoto, Masayuki Shimojo, Kazutaka Mitsuishi, and Masaki Takeguchi

Theta Rotation and Serial Registration of Light Microscopical Images Using a Novel Camera Rotating Device 239

Bradley S. Duerstock, John Cirillo, and Bartek Rajwa

Using DTSa-II to Simulate and Interpret Energy Dispersive Spectra from Particles 248

Nicholas W.M. Ritchie

Key Parameters Affecting Quantitative Analysis of STEM-EDS Spectrum Images 259

Chad M. Parish and Luke N. Brewer

Confidence Bounds for the Estimation of the Volume Phase Fraction from a Single Image in a Nickel Base Superalloy 273

Rémi Blanc, Pierre Baylou, Christian Germain, and Jean-Pierre Da Costa

MATERIALS APPLICATIONS

Focused Ion Beam Characterization of Bicomponent Polymer Fibers 282

K.C. Wong, C.M. Haslauer, N. Anantharamaiah, B. Pourdeyhimi, A.D. Batchelor, and D.P. Griffis

Growth Rate Determination through Automated TEM Image Analysis: Crystallization Studies of Doped SbTe Phase-Change Thin Films 291

Jasper L.M. Oosthoek, Bart J. Kooi, Jeff T.M. De Hosson, Rob A.M. Wolters, Dirk J. Gravensteijn, and Karen Attenborough

Defect and Interfacial Structure of Heteroepitaxial Fe₃O₄/BaTiO₃ Bilayers 300

Sujing Xie, George E. Sterbinsky, Bruce W. Wessels, and Vinayak P. Dravid

BIOLOGICAL APPLICATIONS

Polarized-Light Interferometry of Calcium Carbonate Deposition in Moss from a Waterfall on the Niagara Escarpment 306

Howard J. Swatland

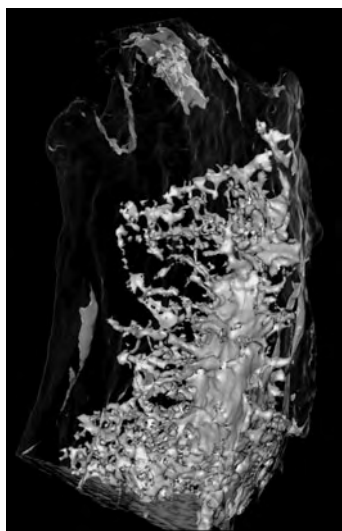
Visualization of the Orai1 Homodimer and the Functional Coupling of Orai1-STIM1 by Live-Cell Fluorescence Lifetime Imaging 313

Ping-Chun Huang, Tai-Yu Chiu, Li-Chun Wang, Hsiao-Chuan Teng, Fu-Jen Kao, and De-Ming Yang

Nanoscale X-Ray Microscopic Imaging of Mammalian Mineralized Tissue 327

Joy C. Andrews, Eduardo Almeida, Marjolein C.H. van der Meulen, Joshua S. Alwood, Chialing Lee, Yijin Liu, Jie Chen, Florian Meirer, Michael Feser, Jeff Gelb, Juana Rudati, Andrei Tkachuk, Wenbing Yun, and Piero Pianetta

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On the Cover: 3D tomographic reconstruction of lacuna from mouse tibia. For further information see Andrews et al. on pp. 327–336.

Contents continued

Ultrastructural Imaging of *Candida albicans* Adhesion to Rat Genital Epithelium through Scanning and Transmission Electron Microscopy 337
Edilson Damke, Agenor Storti-Filho, Mary M.T. Irie, Márcia A. Carrara, Marcia R. Batista, Lucélia Donatti, Luciene S.A. Gunther, Eliana V. Patussi, Terezinha I.E. Svizdinski, and Márcia E.L. Consolaro

Electron Beam-Induced Radiation Damage: The Bubbling Response in Amorphous Dried Sodium Phosphate Buffer 346
William H. Massover

BOOK REVIEW

Handbook of Sample Preparation for Scanning Electron Microscopy and X-Ray Microanalysis. Patrick Echlin 358
Iolo ap Gwynn

CALENDAR OF MEETINGS AND COURSES 360

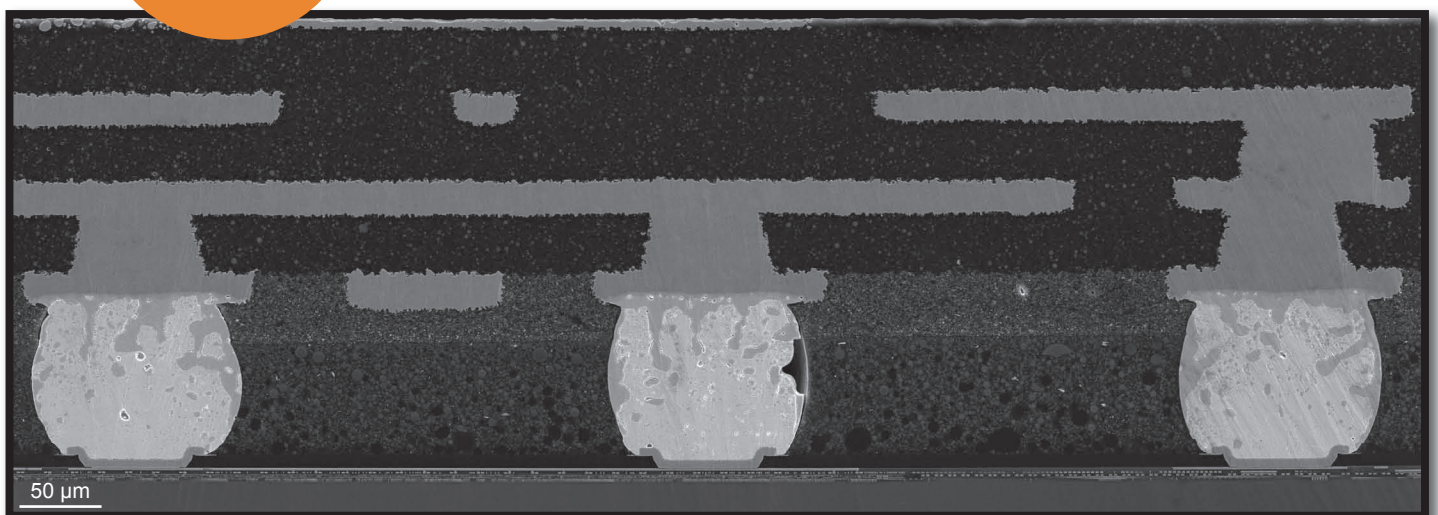
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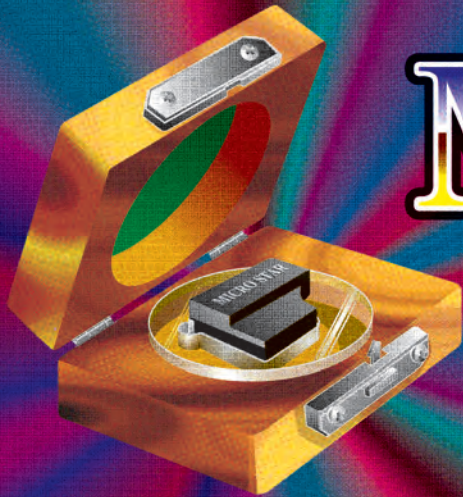
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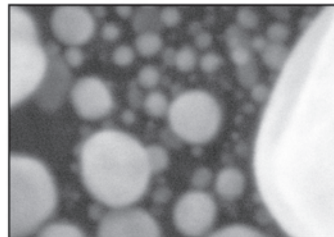


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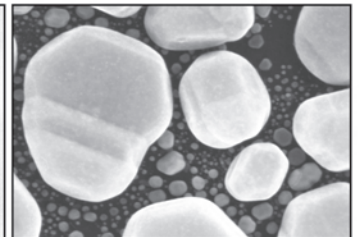
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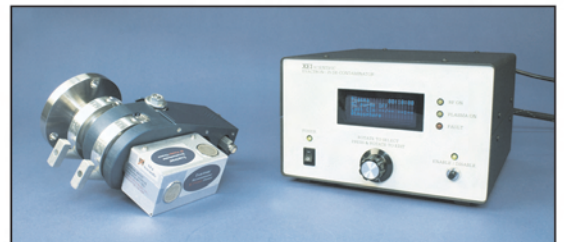
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ultra 45° the first diamond knife with an absolutely score-free, hydrophilic cutting edge.

semi the first diamond knife for alternating sectioning ultrathin/semithin.

cryo the diamond knife for sectioning at low temperature.

histo the first diamond knife for semithin sections for light microscopy.

ultra 35° the diamond knife for optimized sectioning results in almost all applications.

STATIC LINE II the ionizer for eliminating electrostatic charging in ultramicrotomy.

cryo-P a cryo knife with a patented platform for section pick up.

cryo immune the optimized cryo diamond knife for the Tokuyasu technique.

ultra sonic the oscillating diamond knife for room temperature sectioning.

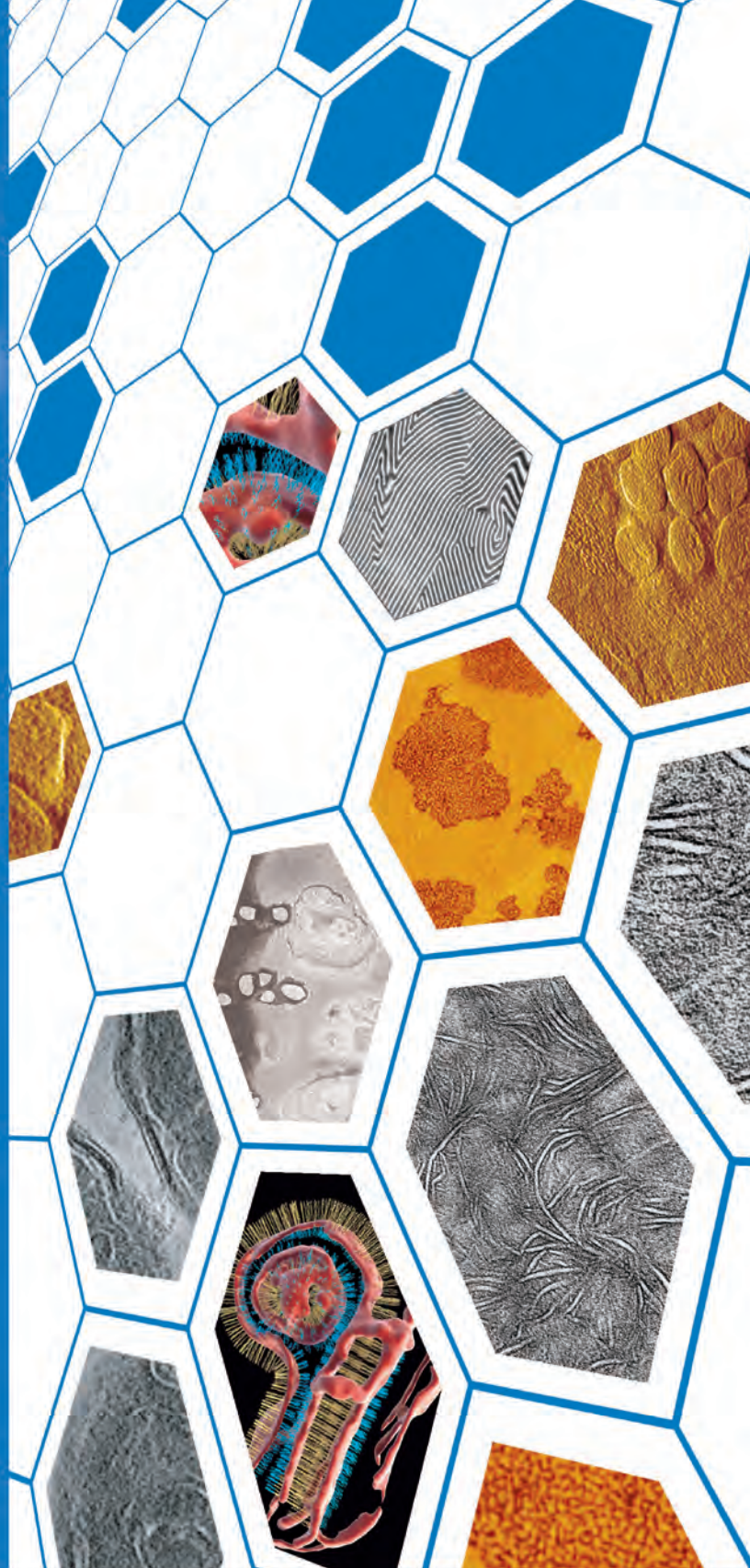
cryotrim 45 and 25 optimizing trimming with diamond blades.

ultra AFM & cryo AFM the first diamond knives for AFM at room and low temperatures.

cryo 25° for sectioning frozen hydrated specimens.

What services can we offer you?

- Technical assistance in all fields of ultramicrotomy.
- Free sectioning tests for all types of samples.
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- Custom knives, tools, and boats.
- Special purchase programs.
- Workshops and training.



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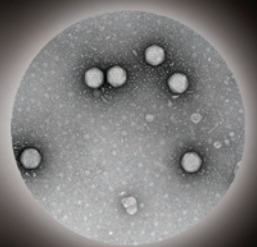
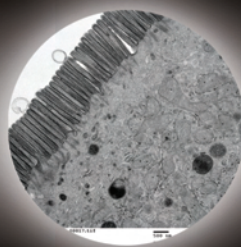
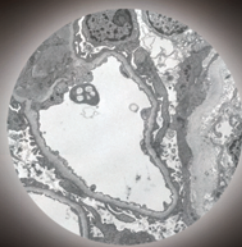
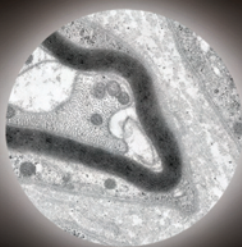
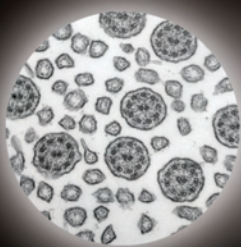
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